

August 31, 1999

Federal Communications Commission Authorization and Evaluation Division 7435 Oakland Mills Road Columbia, MD 21046

Attention:	Applications Examiner
Reference:	FCC ID: HOLCL990 CIDCO Model CL990 Cordless Telephone Base Unit

Dear Examiner:

The following equipment authorization application is presented on behalf of CIDCO, Inc. for the certification of their Model CL990 Cordless Telephone Base unit. Enclosed, please find complete data and documentation package demonstrating that this device complies with the technical requirements of 47 CFR, Part 15, Subpart C for an Intentional Radiator. The manufacturer seeks authorization under the FCC ID: HOLCL990.

We look forward to an expeditious review of the report presented and a granting of the certification for CIDCO, Inc. If you have any questions or we can be of assistance, in this matter, please call us at (410) 354-3300.

Best regards,

Chris Harvey EMC Laboratory Director, MET Laboratories, Inc.

Enclosures



MET Laboratories, Inc. Safety Certification - EMI - Telecom Environmental Simulation 914 WEST PATAPSCO AVENUE ! BALTIMORE, MARYLAND 21230-3432 ! PHONE (410) 354-3300 ! FAX (410) 354-3313

ENGINEERING TEST REPORT

in support of the Application for Grant of Equipment Authorization

EQUIPMENT:	Model CL990 Cordless Telephone Base Unit
FCC IDENTIFIER:	HOLCL990
SPECIFICATION:	15.247(a) thru (e); 15.209(a).
Manufacturer:	CIDCO , Inc. 220 Cochrane Circle Morgan Hill, CA 95037
TESTING DATE(S):	21 and 23 July 1999
MANUFACTURER'S REPRESENTATIVE:	Mr. Can Nguyen

ENGINEERING STATEMENT

I ATTEST: the measurements shown in this report were made in accordance with the procedures indicated, and that the emissions from this equipment were found to be within the limits applicable. I assume full responsibility for the accuracy and completeness of these measurements, and for the qualifications of all persons taking them.

Alvin Ilarina Test Engineer, MET Laboratories, Inc.



MODIFICATIONS STATEMENT

I ATTEST: that the product will be manufactured with all modifications for Part 15 compliance as submitted in this report. Modifications made during testing appear below:

1. No modifications were made to the EUT.

1.0 INTRODUCTION

The following test report is presented on behalf of the Applicant, as verification of the compliance of the CIDCO Direct Sequence, Spread-Spectrum Telephone Base unit, Model: CL990.

2.0 TEST SITE

All testing was conducted at MET Laboratories, Inc., 33439 Western Avenue, Union City, CA 94587. A complete site description is on file with the FCC Laboratory Division as 31040/SIT/MET.

Manufacturer	Equipment	Calibration Due	Cal. Interval
Hewlett Packard	8593EM Spectrum Analyzer	12/1/99	annual
EMCO	Xwing Antenna 1145	4/1/00	annual
EMCO	Active Rod Antenna	2/15/00	annual
EMCO	Double Ridge Horn 3115	2/4/00	annual
EMCO	LISN 3825/2	9/29/99	annual
Schaffner	Biconilog Antenna	4/30/00	annual

3.0 TEST EQUIPMENT USED

4.0 TEST CONFIGURATION

The CIDCO Cordless Telephone Base model CL990, was configured with the Model: CL9HS Handset in accordance with the manufacturer's instructions and operated in a manner representative of the typical usage of the equipment. During testing of the EUT, the Base unit Model # CL990 was manipulated within the confines of typical usage to maximize each emission.



6.0 TEST TYPE(S)

- 6.1 As required by §15.247(b) of CFR 47, *output power measurements* radiated measurements were performed to verify compliance with the conducted limit.
- 6.2 As required by §15.247(a)(2) of CFR 47, 6 *dB* bandwidth measurements were performed
- 6.3 As required by §15.247(e) of CFR 47, *processing gain* Measurements were not performed. Data is provided instead, by the spread spectrum chipset manufacturer
- 6.4 As required by \$15.247(c)(1)& (c)(2) of CFR 47, *out of band emissions measurements* were performed.
- 6.5 As required by §15.247(d) of CFR 47, power density measurements were performed
- 6.6 As required by §15.107 of CFR 47, Line Conducted Emission measurements were performed

7.0 EUT CONFIGURATION INFORMATION

Equipment:	Base Station (900MHz Cordless Telephone)
Model #:	CL990
Serial #:	not provided
FCC ID:	HOLCL990
Equipment:	Handset (900MHz cordless Telephone)
Model #:	CL9HS
Serial #:	not provided
FCC ID:	HOLCL9HS

Special Note:

6.7 As required by §15.214 of CFR 47, *Security code requirments* were met based on the nature of the technology used. The EUT uses Direct Sequence, Spread Spectrum Technology which provides adequate security for any unintended receivers of the intended signal.



Photograph(s) of Radiated Emissions Test Configuration

CIDCO Model CL990 Cordless Telephone





Photograph(s) of Line Conducted Emissions Test Configuration

CIDCO Model CL990 Cordless Telephone Base





SUBJECT:	Peak Output Power	MET REPORT:	EMIU9561B
	15.247(b)	MFG:	CIDCO
	FCC Part 15, Subpart C	TESTED BY:	Alvin Ilarina
	Intentional Radiator	TEST DATE(S):	23 July 1999
	Intentional Radiator	TEST DATE(S):	23 July 1999

EUT: CIDCO MODEL: CL990 (Telephone Base unit)

TECHNICAL SPECIFICATION: 15.247(b)

CARRIER POWER:

Peak Output power was calculated through the following means:

The raw reading from the analyzer was added to the cable loss and antenna factor (for the specific frequency of measurement). The final E-field strength limit is derived from the conversion of the power limit specified in FCC Part. 15.247(b) to V/m, considering a 50Ω system.

Please see the attached plots

Handset/ Base	Freq (MHz)	Worst case Raw+ACF Reading (dBuV/m)	Dist (m)	Cbl/HPF/C on Loss (dB)	Pre amp (dB)	Corr level (dBµV/m)	Total (V/m)	Total watts
Base	904.17	112.56	3.0	2.7*	n/a	115.26	0.579	0.101

* - Cable losses only. No High-pass filter (i.e. insertion loss) factors, etc., associated with measurement.

The Model CL990 system results for the Base are provided as the highest level of the system. (Across the entire channel range)

Frequency Range (MHz)	Frequency (MHz)	Measured Signal (V/m)	E limit (V/m)	E margin (dB)
902-928	904.17	0.579	3.64	16.02



SUBJECT:	6 dB Bandwidth	MET REPORT:	EMIU9561B
	15.247(a)(2)	MFG:	CIDCO
	FCC Part 15, Subpart C	TESTED BY:	Alvin Ilarina
	Intentional Radiator	TEST DATE(S):	23 July 1999

EUT:CIDCOMODEL:CL990 Base Unit

TECHNICAL SPECIFICATION: 15.247(a)(2)

Please see the attached plots

The 6 dB bandwidth was determined from the plot provided as follows:

EUT	Frequency (MHz)	6 dB Bandwidth (MHz)
Base	926.025 (worst case)	1.71





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SUBJECT: Processing Gain 15.247(e) FCC Part 15, Subpart C Intentional Radiator

MET REPORT: MFG: TESTED BY: DATE: EMIU9561B CIDCO Alvin Ilarina (Provided by chipset Manufacturer)

EUT: CIDCO MODEL: CL990 (Telephone Base unit)

TECHNICAL SPECIFICATION: 15.247(e)

Processing Gain Measurements, per CFR 47, Part 15.247(e) were performed by the spread spectrum chipset manufacturer, Rockwell Semiconductor. Testing results as performed by Rockwell, have been included for reference and comparrison to the applicable limit.

Refer to the following 3 pages for tables, notes, and data, from the processing gain measurements provided by the spread spectrum chip manufacturer:



Introduction

1.1 Scope

This document is a Rockwell Semiconductor Systems (RSS) Engineering report. This document details the results of measurement of the processing gain of a DCT FFF phone.

1.2 Intended Readers

The intended readers of this document are RSS marketing, application, engineering, test engineering, technical publication, and management personnel. This document is not intended for distribution outside of RSS.

1.3 Reference Documents

This section lists documents that are referenced within or are materially relevant to this document.

Code of Federal Regulations, Title 47, Chapter 1, Part 15 Radio Frequency Devices (FCC)

1.4 Definitions

FCC	Federal Communications Commission		
SNR	Signal to Noise Ratio		
JSR	Jammer to Signal Ratio		
CW	Continuous wave (jammer)		
HS	Handset		
BS	Basestation		
DBPSK	Differential Binary Phase Shift Keying		

Table 1: Definitions and Abbreviations

2. An Overview of the FCC Method for measuring Processing Gain

Two methods are specified for measuring processing gain by the FCC in 15.247 (e). The first method simply involves calculating the signal to ratio noise (SNR) with the spreading code switched on with the SNR when the spreading code is switched off. The difference between the two is the processing gain. The SNR is measured at the demodulated output of the receiver. In principle this an acceptable method to measure the processing gain of any direct sequence spread spectrum communication system, however, it does not take into consideration that the non-spread spectrum portion of the system may operate under the assumption that the signal being transmitted is a spread spectrum signal and when the spreading code is switched off the system may fail to operate or operate at greatly reduced efficiency. In either case the measurement of processing gain will be meaningless.

The second method specified by the FCC to measure processing gain is detailed in 15.247 (e)(1). This involves transmitting a CW jammer in the RF passband of the system and measuring the jammer to signal ratio (JSR) required to achieve a certain bit error rate. The choice of the actual value of the bit error rate is left up to the tester. The jammer is stepped in 50 kHz increments across the entire passband and in each case the JSR to achieve the desired bit error rate is measured. The JSR is measured at the RF input to the system under test.

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The lowest 20% of the JSR data (in dB) is discarded. The processing gain can then be calculated as follows:-

 $G_P = (S/N)_{theory} + (J/S)_{meas} + L_{system}$

where G_p is the processing gain, the SNR is that theoretically predicted for the system under the test to achieve the desired bit error rate, the JSR is the lowest value (in dB) in the remaining data set and L_{sys} adjusts for nonideal system losses. L_{sys} can not be greater than 2 dB.

3. Processing Gain Measurement Results

The following parameters were used in the test setup.

HS Tx power (dBm)	-1.9	
BS LNA gain (dB)	0	
Channel attenuation (dB)	-50	
Test system losses (signal) (dB)	-11.75	-4.05 dB (system), -6 dB (signal combiner), -1.7 dB (2 cables)
Test system losses (jammer) (dB)	-12.85	-12 dB (signal combiner), -0.85 dB (cable)

Table 2: Test Setup Parameters

Jammer Frequency	BER (BS)	Received jammer	Received signal	Jammer/Signal ratio
913.80	9.4×10 ⁻⁴	-59.55	-63.65	4.1
913.85	9.6×10 ⁻⁴	-57.95	-63.65	5.7
913.90	9.6×10⁻⁴	-60.15	-63.65	3.5
913.95	9.6×10 ⁻⁴	-64.25	-63.65	-0.6
914.00	1.1×10 ⁻³	-61.55	-63.65	2.1
914.05	9.8×10 ⁻⁴	-61.55	-63.65	2.1
914.10	1.1×10 ⁻³	-61.95	-63.65	1.7
914.15	9.2×10 ⁻⁴	-62.85	-63.65	0.8
914.20	1.0×10 ⁻³	-59.85	-63.65	3.8
914.25	1.0×10 ⁻³	-61.15	-63.65	2.5
914.30	1.1×10 ⁻³	-62.05	-63.65	1.6
914.35	1.0×10 ⁻³	-57.65	-63.65	6.0
914.40	1.1×10 ⁻³	-55.65	-63.65	8.0
914.45	1.0×10 ⁻³	-49.35	-63.65	14.3
914.50	1.1×10 ⁻³	-59.25	-63.65	4.4
914.55	1.0×10 ⁻³	-62.35	-63.65	1.3
914.60	9.7×10⁻⁴	-59.05	-63.65	4.6
914.65	1.0×10 ⁻³	-61.05	-63.65	2.6
914.70	1.1×10 ⁻³	-62.55	-63.65	1.1
914.75	9.0×10 ⁻⁴	-61.95	-63.65	1.7
914.80	1.0×10 ⁻³	-61.05	-63.65	2.6
914.85	9.9×10 ⁻⁴	-62.35	-63.65	1.3
914.90	1.1×10 ⁻³	-64.05	-63.65	-0.4
914.95	9.2×10 ⁻⁴	-56.25	-63.65	7.4
915.00	1.0×10 ⁻³	-59.85	-63.65	3.8
915.05	1.1×10 ⁻³	-57.25	-63.65	6.4
915.10	9.9×10 ⁻⁴	-58.15	-63.65	5.5

Table 3: Test Results





Figure 1: Test Setup

For DBPSK at 10^{-3} bit error rate the required SNR is 8.0 dB. Using the results above and the data in the table below the processing gain is calculated to be 11.3 dB.

required SNR (dB)	8.0
system losses (dB)	2.0
J/S ratio at 80% point (dB)	1.30
FCC Processing gain (dB)	11.3

Table 4: Processing Gain Calculation data

4. Conclusions

The result measured for processing gain of 11.3 dB is close to the actual processing gain due to a 12 chip spreading code of

$$10 \times \log_{10}(12) = 10.8 \, dB$$



Spurious Emissions	MET REPORT:	EMIU9561B
15.247(c)(paragraphs 1 & 2)	MFG:	CIDCO
FCC Part 15, Subpart C	TESTED BY:	Alvin Ilarina
Intentional Radiator	TEST DATE(S):	23 July 1999
	Spurious Emissions 15.247(c)(paragraphs 1 & 2) FCC Part 15, Subpart C Intentional Radiator	Spurious EmissionsMET REPORT:15.247(c)(paragraphs 1 & 2)MFG:FCC Part 15, Subpart CTESTED BY:Intentional RadiatorTEST DATE(S):

EUT:CIDCOMODEL:CL990 (Telephone Base unit)

TECHNICAL SPECIFICATION: 15.247(c)(paragraphs 1 & 2)

The limits, as illustrated on the following table were derived from the following:

The marker was placed on the highest emission inside the band and the marker recorded.

w/ RBW = 100 kHz, the highest emission within the band of operation was found to be = 115.26 dBuV. Therefore;

all spurs harmonics must be 115.26 - 20 dB = 95.26 dBuV.

spurs that fall in Restricted Band (per 15.205) must meet the limits of 15.209 (i.e. 54 dBuV):



Freq (GHz)	Ant orient H/V	Raw Reading (dBµV)	Ant Factor (dB/m)	Cbl/HPF/ Conn Loss (dB)	d (m)	d corr (dB)	Corr. Level (dBµV/m)	Limits (dBµV/m)	Comments
0.2202	Н	25.40	10.1	1.2	3.0	0.0	36.7	46.0	Restricted band
0.2202	V	16.01	11.3	1.2	3.0	0.0	28.51	46.0	Restricted band
1.103	Н	33.8	23.5	2.12	1.0	- 9.54	49.88	54.0	Restricted Band
1.103	V	34.07	23.6	2.12	1.0	- 9.54	49.66	54.0	Restricted Band
1.820	Н	29.7	24.9	3.15	1.0	-9.54	48.21	95.26	Spur
1.820	V	31.2	25.0	3.15	1.0	- 9.54	49.81	95.26	Spur
2.960	н	32.1	30.4	4.2	1.0	- 9.54	57.16	95.26	Spur
2.960	V	32.08	30.4	4.2	1.0	- 9.54	57.06	95.26	Spur
4.470	Т	15.7	33.0	7.0	1.0	-9.54	46.16	95.26	Spur
4.470	v	15.69	32.7	7.0	1.0	-9.54	45.76	95.26	Spur
10.000	Н	24.3	38.3	10.1	1.0	-9.54	63.16	95.26	Spur
10.000	V	24.2	38.2	10.1	1.0	-9.54	62.96	95.26	Spur

*Note - All levels taken above, were with VBW set to 10 Hz to simulate an average measurement. These levels are pulsed in nature, but HAVE NOT been adjusted for the peak-average correction factor.



SUBJECT:	Transmitted Power Spectural Density	MET REPORT:	EMIU9561B
	15.247(d)	MFG:	CIDCO
	FCC Part 15, Subpart C	TESTED BY:	Alvin Ilarina
	Intentional Radiator	TEST DATE(S):	23 JUL 1999

EUT: CIDCO MODEL: CL990 TECHNICAL SPECIFICATION: 15.247(d)

Power density limit is stated as +8 dBm.

Test data is presented on the plots following this section:

Base : Model: CL990 (Telephone base unit)

The largest value found within a 3 kHz bandwidth for the Base unit of the EUT, was found to be:

For the Base : $-36.0 \text{ dBm} + 23.4 \text{ dB} = -12.6 \text{ dBm} \text{ or } 94.4 \text{ dB}\mu\text{V/m}$ (or 0.053 V/m).

(Note: were 23.44 dB is Aantenna Factor for antenna used.)

• Solving the above for power density output using the equation: $P_D = (\underline{E} \cdot \underline{d})^2$ 30 G

Where; E = 0.053 V/m $\,$, d = $\,$ 3.0 $\,$ m , and $\,$ G = 1.0 for isotropic antenna

Therefore; $P_D = (0.053 * 3)^2 / 30(1) = 0.008004 \text{ W} \text{ or } 0.8 \text{ mW}$

 $P_D = 0.8 \text{ mW} = -1 \text{ dBm}_{\text{meas}}$

 P_D Limit = +8 dBm

Please see the following 5 plots on the next 3 pages.

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SUBJECT:Conducted Emissions
Neutral SideMET REPORT:
MFG:EMIU9561B
CIDCOFCC Part 15, Subpart C
Intentional RadiatorTESTED BY:
TEST DATE(S):Alvin Ilarina
23 Jul 99

EUT:CIDCOMODEL:CL990 (Telephone Base unit)

TECHNICAL SPECIFICATION:

Equipment meets the specifications of Part 15.207(a)

Frequen cy (MHZ)	Quasi- Peak Level (dBµV)	Limit (dBµV)
27.5	44.50	47.95
0.678	42.00	47.95
0.783	41.20	47.95

SUMMARY — 3 Worst-Case Emissions



SUBJECT:Conducted EmissionsMET REPORT:EMIU9561BPhase SideMFG:CIDCOFCC Part 15, Subpart CTESTED BY:Alvin IlarinaIntentional RadiatorTEST DATE(S):26 May 1999

EUT:CIDCOMODEL:CL990 (Telephone Base unit)

TECHNICAL SPECIFICATION: 15.207(a)

LIMITS: 0.45 - 1.705 MHZ : 250 μV (47.9 dBμV)

Equipment meets the specifications of Part 15.107(a)

Frequency (MHz)	Level (dBµV)	Limit (dBµV)
0.535	42.00	47.95
0.738	41.56	47.95
3.25	39.97	47.95

SUMMARY — 3 Worst-Case Emissions